

January 1995 Revised November 1999

# 74ABT241

# Octal Buffer/Line Driver with 3-STATE Outputs

## **General Description**

The ABT241 is an octal buffer and line driver with 3-STATE outputs designed to be employed as a memory and address driver, clock driver, or bus-oriented transmitter/

#### **Features**

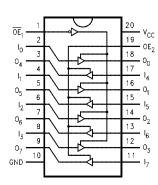
- Non-inverting buffers
- Output sink capability of 64 mA, source capability of 32 mA
- Guaranteed latchup protection
- High impedance glitch free bus loading during entire power up and power down cycle
- Nondestructive hot insertion capability

# **Ordering Code:**

Order Number	Package Number	Package Description					
74ABT241CSC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide Body					
74ABT241CSJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide					
74ABT241CMSA	MSA20	20-Lead Shrink Small Outline Package (SSOP), EIAJ TYPE II, 5.3mm Wide					
74ABT241CMTC	MTC20	20-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide					

Device also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

# **Connection Diagram**



#### **Pin Descriptions**

Pin Names	Description
OE <sub>1</sub>	Output Enable Input (Active LOW)
OE <sub>2</sub>	Output Enable Input (Active HIGH)
I <sub>0</sub> –I <sub>7</sub>	Inputs
O <sub>0</sub> -O <sub>7</sub>	Outputs

### **Truth Table**

OE <sub>1</sub>	I <sub>0-3</sub>	O <sub>0-3</sub>	OE <sub>2</sub>	I <sub>4-7</sub>	O <sub>4-7</sub>
Н	Х	Z	L	X	Z
L	Н	Н	Н	Н	Н
L	L	L	Н	L	L

- H = HIGH Voltage Level L = LOW Voltage Level

- X = Immaterial Z = High Impedance

# **Absolute Maximum Ratings**(Note 1)

-65°C to +150°C

Ambient Temperature under Bias  $-55^{\circ}$ C to  $+125^{\circ}$ C Junction Temperature under Bias  $-55^{\circ}$ C to  $+150^{\circ}$ C

V<sub>CC</sub> Pin Potential to Ground Pin -0.5V to +7.0V

 $\begin{array}{ll} \mbox{Input Voltage (Note 2)} & -0.5 \mbox{V to } +7.0 \mbox{V} \\ \mbox{Input Current (Note 2)} & -30 \mbox{ mA to } +5.0 \mbox{ mA} \\ \end{array}$ 

Voltage Applied to Any Output

in the Disabled or

Storage Temperature

Power-Off State -0.5V to 5.5V in the HIGH State -0.5V to  $V_{CC}$ 

Current Applied to Output

in LOW State (Max) twice the rated I<sub>OL</sub> (mA)

DC Latchup Source Current

(Over Comm Operating Range) -500 mA

Over Voltage Latchup (I/O)

# Recommended Operating Conditions

Free Air Ambient Temperature -40°C to +85°C Supply Voltage +4.5V to +5.5V

Minimum Input Edge Rate ( $\Delta V/\Delta t$ )

Data Input 50 mV/ns
Enable Input 20 mV/ns

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation

under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

#### **DC Electrical Characteristics**

Symbol	Param	eter	Min	Тур	Max	Units	v <sub>cc</sub>	Conditions
V <sub>IH</sub>	Input HIGH Voltage		2.0			V		Recognized HIGH Signal
V <sub>IL</sub>	Input LOW Voltage				0.8	V		Recognized LOW Signal
V <sub>CD</sub>	Input Clamp Diode Voltage				-1.2	V	Min	I <sub>IN</sub> = -18 mA
V <sub>OH</sub>	Output HIGH Voltage		2.5			V	Min	$I_{OH} = -3 \text{ mA}$
		2.0			V	Min	I <sub>OH</sub> = -32 mA	
V <sub>OL</sub>	Output LOW Voltage				0.55	V	Min	I <sub>OL</sub> = 64 mA
I <sub>IH</sub>	Input HIGH Current				1 1	μΑ	Max	V <sub>IN</sub> = 2.7V (Note 4) V <sub>IN</sub> = V <sub>CC</sub>
I <sub>BVI</sub>	Input HIGH Current B	reakdown Test			7	μА	Max	V <sub>IN</sub> = 7.0V
I <sub>IL</sub>	Input LOW Current				−1 −1	μА	Max	V <sub>IN</sub> = 0.5V (Note 4) V <sub>IN</sub> = 0.0V
V <sub>ID</sub>	Input Leakage Test		4.75			V	0.0	I <sub>ID</sub> = 1.9 μA All Other Pins Grounded
I <sub>OZH</sub>	Output Leakage Current				10	μΑ	0 – 5.5V	$V_{OUT} = 2.7V; \overline{OE}_n = 2.0V$
I <sub>OZL</sub>	Output Leakage Current				-10	μΑ	0 – 5.5V	$V_{OUT} = 0.5V; \overline{OE}_n = 2.0V$
Ios	Output Short-Circuit Current		-100		-275	mA	Max	V <sub>OUT</sub> = 0.0V
I <sub>CEX</sub>	Output High Leakage Current				50	μΑ	Max	V <sub>OUT</sub> = V <sub>CC</sub>
I <sub>ZZ</sub>	Bus Drainage Test				100	μΑ	0.0	V <sub>OUT</sub> = 5.5V; All Others GND
I <sub>CCH</sub>	Power Supply Current	t			50	μΑ	Max	All Outputs HIGH
I <sub>CCL</sub>	Power Supply Current	t			30	mA	Max	All Outputs LOW
I <sub>CCZ</sub>	Power Supply Current	t			50	μА	Max	$\overline{OE}_n = V_{CC};$ All Others at $V_{CC}$ or Ground
I <sub>CCT</sub>	Additional I <sub>CC</sub> /Input	Outputs Enabled			2.5	mA		$V_{I} = V_{CC} - 2.1V$
		Outputs 3-STATE			2.5	mA	Max	Enable Input V <sub>I</sub> = V <sub>CC</sub> - 2.1V
		Outputs 3-STATE			50	μΑ		Data Input $V_I = V_{CC} - 2.1V$ All Others at $V_{CC}$ or Ground
I <sub>CCD</sub>	Dynamic I <sub>CC</sub>	Dynamic I <sub>CC</sub> No Load				mA/ MHz		Outputs Open
	(Note 4)				0.1		Max	$\overline{OE}_n = GND$ , (Note 3)
								One Bit Toggling, 50% Duty Cycle

10V

Note 3: For 8 bits toggling, I<sub>CCD</sub> < 0.8 mA/MHz.

Note 4: Guaranteed, but not tested.

### **DC Electrical Characteristics**

(SOIC package)

Symbol	Parameter	Min	Тур	Мах	Units	V <sub>cc</sub>	Conditions $C_L = 50 \text{ pF},$ $R_L = 500\Omega$
V <sub>OLP</sub>	Quiet Output Maximum Dynamic V <sub>OL</sub>		0.5	8.0	V	5.0	T <sub>A</sub> = 25°C (Note 5)
V <sub>OLV</sub>	Quiet Output Minimum Dynamic V <sub>OL</sub>	-1.3	-0.8		V	5.0	T <sub>A</sub> = 25°C (Note 5)
V <sub>OHV</sub>	Minimum HIGH Level Dynamic Output Voltage	2.7	3.1		V	5.0	T <sub>A</sub> = 25°C (Note 7)
$V_{IHD}$	Minimum HIGH Level Dynamic Input Voltage	2.0	1.5		V	5.0	T <sub>A</sub> = 25°C (Note 6)
$V_{ILD}$	Maximum LOW Level Dynamic Input Voltage		1.1	0.8	V	5.0	T <sub>A</sub> = 25°C (Note 6)

Note 5: Max number of outputs defined as (n). n – 1 data inputs are driven 0V to 3V. One output at LOW. Guaranteed, but not tested.

Note 6: Max number of data inputs (n) switching. n – 1 inputs switching 0V to 3V. Input-under-test switching: 3V to threshold (V<sub>ILD</sub>), 0V to threshold (V<sub>IHD</sub>). Guaranteed, but not tested.

Note 7: Max number of outputs defined as (n). n - 1 data inputs are driven 0V to 3V. One output HIGH. Guaranteed, but not tested.

#### **AC Electrical Characteristics**

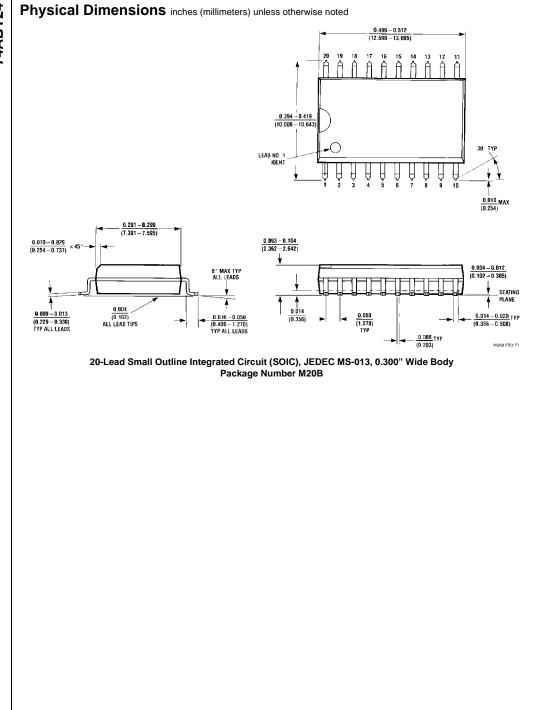
(SOIC and SSOP package)

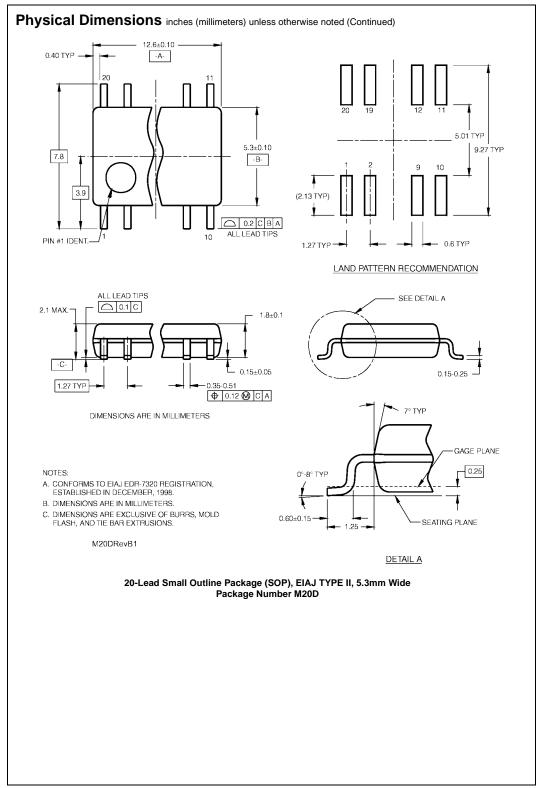
Symbol	Parameter	$T_A = +2!$ $V_{CC} = +$ $C_L = 50$		$T_A = -40^{\circ}\text{C to } +85^{\circ}\text{C}$ $V_{CC} = 4.5\text{V} - 5.5\text{V}$ $C_L = 50 \text{ pF}$		Units	
		Min	Тур	Max	Min	Max	
t <sub>PLH</sub>	Propagation Delay	1.0		4.6	1.0	4.6	20
t <sub>PHL</sub>	Data to Outputs	1.0		4.6	1.0	4.6	ns
t <sub>PZH</sub>	Output Enable	1.1		6.8	1.1	6.8	ns
t <sub>PZL</sub>	Time	1.3		6.8	1.3	6.8	115
t <sub>PHZ</sub>	Output Disable	1.6		6.8	1.6	6.8	20
$t_{PLZ}$	Time	1.0		5.9	1.0	5.9	ns

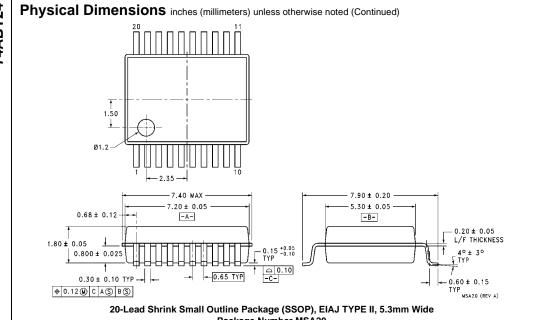
# Capacitance

Symbol	Parameter	Тур	Units	Conditions $T_{\Delta} = 25^{\circ}C$
C <sub>IN</sub>	Input Capacitance	5.0	pF	V <sub>CC</sub> = 0V
C <sub>OUT</sub> (Note 8)	Output Capacitance	9.0	pF	$V_{CC} = 5.0V$

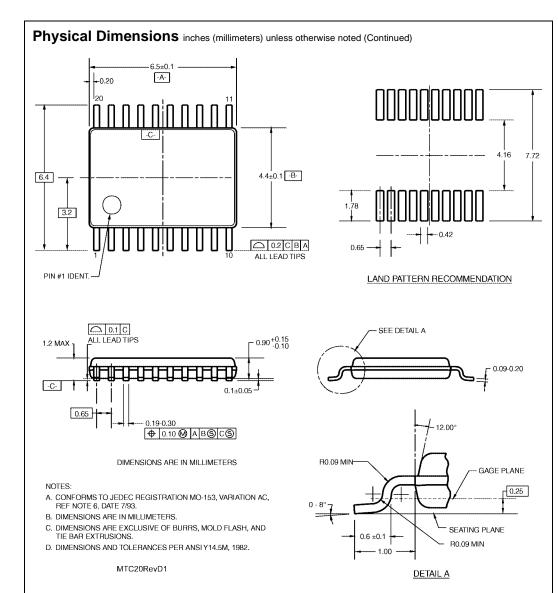
Note 8: C<sub>OUT</sub> is measured at frequency f = 1 MHz, per MIL-STD-883, Method 3012.







20-Lead Shrink Small Outline Package (SSOP), EIAJ TYPE II, 5.3mm Wide Package Number MSA20



# 20-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide Package Number MTC20

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